Abstracts

Accurate characteristic impedance measurement on silicon

D.F. Williams, U. Arz and H. Grabinski. "Accurate characteristic impedance measurement on silicon." 1998 MTT-S International Microwave Symposium Digest 98.3 (1998 Vol. III [MWSYM]): 1917-1920.

This paper presents a new method that accurately determines the characteristic impedance of planar transmission lines printed on lossy dielectrics even when contact-pad capacitance and conductance are large. We demonstrate the method on a coplanar waveguide fabricated on fused silica and a microstrip line fabricated on a highly conductive silicon substrate.

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